

AVS Mid-Atlantic Chapter DC Regional Meeting

Friday, October 14, 2011 9 am - 3 pm
Building 215 National Institute of Standards and Technology
100 Bureau Drive, Gaithersburg, MD

Learn about the advantages of membership in the AVS!

Highlight theme: Novel Activities in Scanning Probe Microscopies

Invited speakers report on regional research

- Matt Bruckman (U.Penn): Probing complex electrical properties at the nanoscale
- Suyong Jung (NIST): Scanning Tunneling Spectroscopy of gated graphene devices in the Quantum Hall regime
- Ichiro Takeuchi (U. MD): Simultaneous imaging of multiple materials properties using high spatial resolution microwave near-field microscopy
- Josephus Ferguson (VCU): Characterization of GaN with scanning Kelvin probe microscopy and AFM

Tours of NIST STM and Nanofabrication Facilities; Nanofab User Info

Equipment Fair—vacuum hardware and instruments

Poster Session open to graduate and undergrad students working in AVS research topics including:

**Biomaterial Interfaces
Electronic Materials & Processes
Magnetic Interfaces & Nanostructures
MEMS & NEMS
Surface Science
Thin Films
Vacuum Technology
Plasma Science**

**Cash Prizes
for the best
student posters**

Pre-registration required -- RSVP deadline* October 7, 2011

*(foreign nationals are encouraged to apply early)

Contact : Jay Hendricks (301)975-4836 jay.hendricks@nist.gov

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Mid-Atlantic Chapter

Science and Technology of Materials, Interfaces and Processing

NIST United States Department of Commerce
National Institute of Standards and Technology